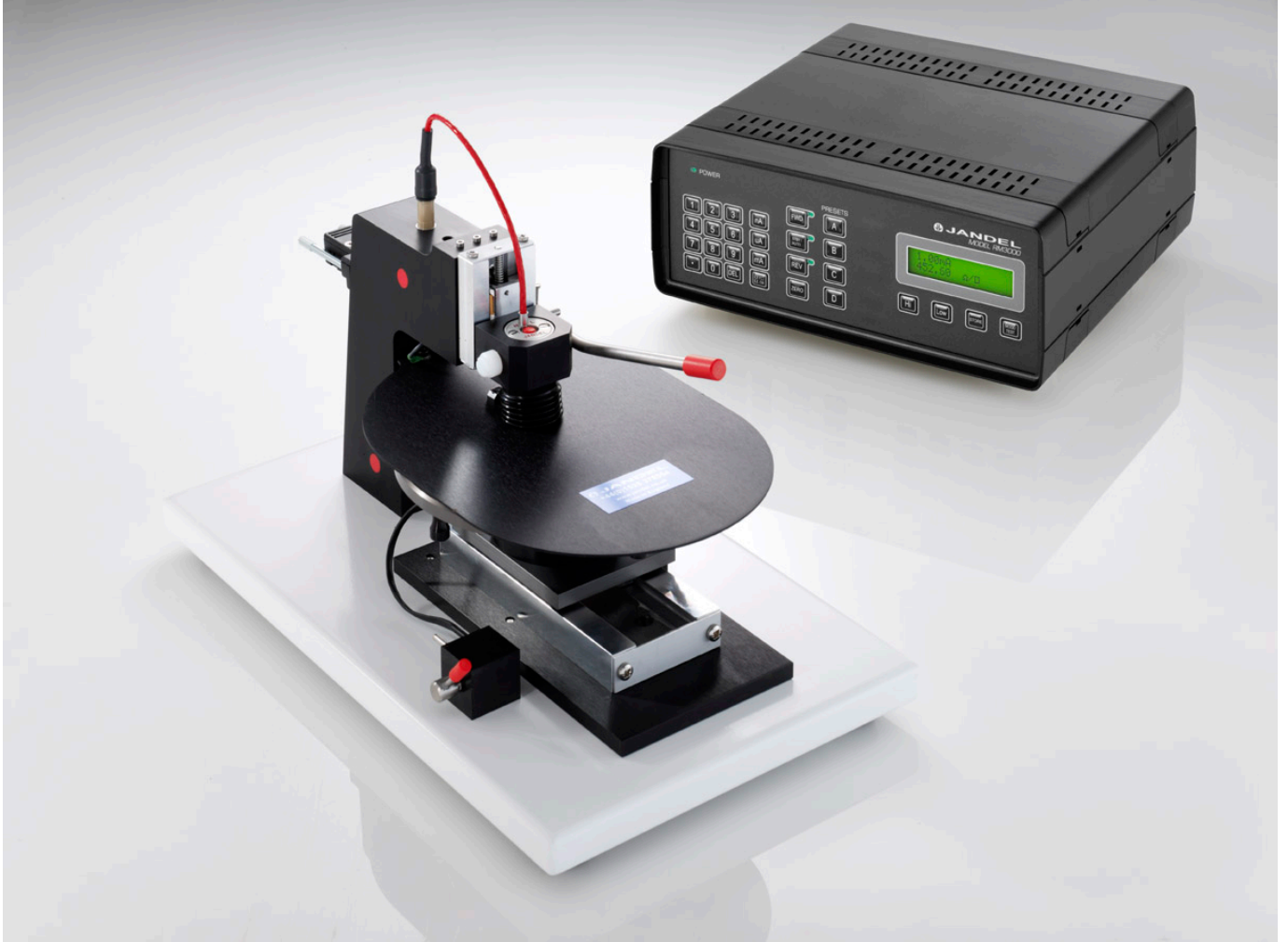


# Jandel Engineering Limited



## Jandel Measurement System for wafers

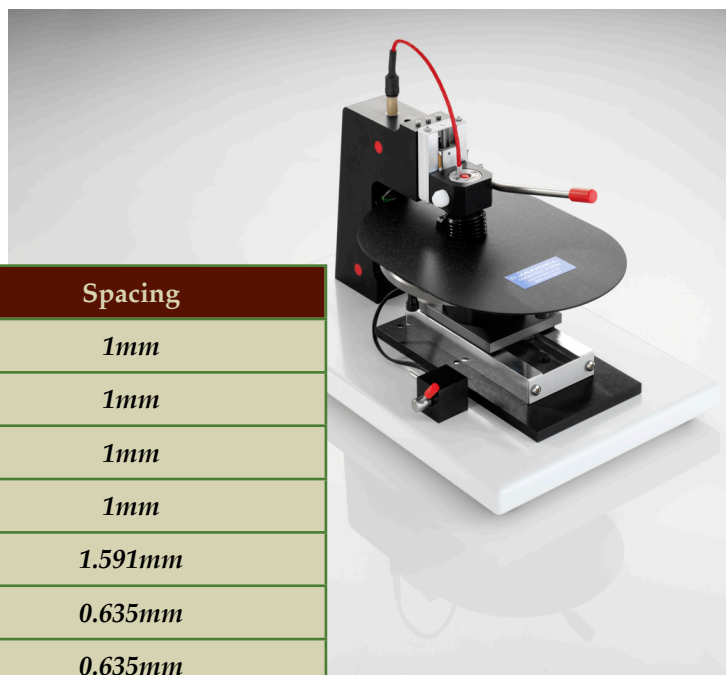
*Jandel Engineering Limited* offers the RM3000 Test Unit in combination with the Multiposition Probe stand as a solution for measurements on wafers (up to 200mm diameter). The probe is available in two sizes at the same cost. One size is for wafers up to 150mm diameter and the second for wafers up to 200mm diameter. If small sized wafers are to be measured the smaller version is more suitable for placement of the wafers on the measurement table. The  $\Theta$  movement clicks in four positions at 90 degrees and the linear movement in up to 10 positions giving repeat placement accuracy of +/- 1mm.

<i>Max. sample size</i>	150mm wafer (200mm wafer on request at no extra cost)
<i>Max. sample thickness</i>	Samples up to 4mm thick can be measured
<i>Microswitch</i>	Prevents current flow when probe is not in contact with the sample
<i>Manual Control</i>	Simple lever operation for probe contact and removal
<i>Simple set up</i>	Single wire connects the probe stand and RM3000
<i>X-Θ Stage</i>	Repositioning accuracy of +/-1mm

## Available Probes

Type	Tip R	Force	Spacing
A	40u	100g	1mm
B	100u	100g	1mm
C	200u	100g	1mm
D	500u	70g	1mm
E	40u	200g	1.591mm
F	40u	100g	0.635mm
G	100u	100g	0.635mm
H	200u	100g	0.635mm

*Type A-D and F-H are user adjustable in the range 60g-150g and supplied at value shown*



*If you require any further information on the Jandel Multipurpose measurement system please contact us using the details below*

Jandel Engineering Limited, Grand Union House, Leighton Road, Leighton Buzzard, LU7 1LA

Telephone: +44 (0) 1525 378554 Fax: +44 (0) 1525 381945 Email: [info@jandel.co.uk](mailto:info@jandel.co.uk)